

Notice of References Cited	Application/Control No. 10/074,851	Applicant(s)/Patent Under Reexamination HARDESTY ET AL.	
	Examiner Anthony Weier	Art Unit 1761	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-3,652,292	03-1972	Bach et al.	426/594
	B	US-4,985,271	01-1991	Neilson et al.	426/595
	C	US-6,048,567	04-2000	Villagran et al.	426/594
	D	US-6,207,203	03-2001	Atkinson et al.	426/73
	E	US-6,399,131	06-2002	Zeller et al.	426/520
	F	US-6,669,979	12-2003	Zhao et al.	426/595
	G	US-5,332,591	07-1994	Ogden, Ralph	426/386
	H	US-1,822,227	09-1931	LENDRICH LOUISE B P; et. al.	426/507
	I	US- 4540,591	9-1985	Dar et al	426/388
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 59-1375 ✓	01-1984	Japan	---	---
	O	JP 59-91845 ✓	05-1984	Japan	---	---
	P	JP 3-133368 ✓	06-1991	Japan	---	---
	Q	JP 11-32680 ✓	02-1999	Japan	---	---
	R	DE 19700368	09-1998	Germany	---	---
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.